Applicant (S

Toshiaki MOTONAGA et al.

HALFTONE PHASE SHIFTING PHOTOMASK AND BLANKS FOR HALFTONE PHASE SHIFTING PHOTOMASK THEREFOR AND A METHOD FOR FORMING PATTERN BY USING THE HALFTONE PHASE SHIFTING PHOTOMASK

MOTRADED

09/825 578

Group:

1756

Confirmation No.: 9940

Filed

April 3, 2001

Examiner: S. Rosasco

International Application No.: N/A

International Filing Date

Atty. Docket No.: OPS Case 529

Commissioner for Patents

RECEIVED

P.O. Box 1450

Alexandria, VA 22313-1450

TC 1700

SEP 0 3 2003

FIRST CLASS MAILING CERTIFICATE

Sir:

I hereby certify that this correspondence is being deposited with the United States Postal Service under 37 CFR 1.8 as first class mail in an envelope addressed to: Commissioner for Patents P.O. Box 1450, Alexandria, VA 22313-1450, on August 27, 2003.

LLC/jp

FLYNN, THIEL, BOUTELL & TANIS, P.C. 2026 Rambling Road Kalamazoo, MI 49008-1631 Phone: (269) 381-1156

Fax: (269) 381-5465 Dale H. Thiel Req. No. 24 323 David G. Boutell Reg. No. 25 072 Reg. No. 22 724 Ronald J. Tanis Terryence F. Chapman Reg. No. 32 549 Mark L. Maki Reg. No. 36 589 David S. Goldenberg Req. No. 31 257 Sidney B. Williams, Jr. Reg. No. 24 949 Reg. No. 40 694 Reg. No. 36 328 Liane L. Churney Brian R. Tumm Robert J. Sayfie Req. No. 37 714

Correspondence:

Information Disclosure Statement dated

August 27, 2003

Copy of Search Report issued June 25, 2003 in

European Application No. 01108402.7

Form PTO-1449 and one copy of each listed

reference Postal Card

190.05/03

9/5/03 #9/JDS

AND 2 9 2000 US

PATENT APPLICATION

IN THE U.S. PATENT AND TRADEMARK OFFICE

August 27, 2003

Applicant(s): Toshiaki MOTONAGA et al.

For: HALFTONE PHASE SHIFTING PHOTOMASK AND BLANKS FOR

HALFTONE PHASE SHIFTING PHOTOMASK THEREFOR AND A METHOD

FOR FORMING PATTERN BY USING THE HALFTONE PHASE

SHIFTING PHOTOMASK

RECEIVED

Serial No.: 09/825 578

Group: 1756

SEP 0 3 2003

Confirmation No.: 9940

TC 1700

Filed: April 3, 2001

Examiner: S. Rosasco

Atty. Docket No.: OPS Case 529

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(c)(1) and 1.98, enclosed is the Search Report issued in the European application corresponding to the instant application, Form PTO-1449, and the references cited therein.

The undersigned hereby certifies under Rule 1.97(e)(1) that each item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement.

Respectfully submitted,

Liane L. Churnev

LLC/jp

· ·	Dale H. Thiel David G. Boutell	Reg. Reg.			_
2026 Rambling Road		Reg.			
Kalamazoo, MI 49008-1631	Terryence F. Chapman	Reg.	No.	32	549
Phone: (269) 381-1156	Mark L. Maki	Reg.	No.	36	589
Fax: (269) 381-5465	David S. Goldenberg	Reg.	No.	31	257
	Sidney B. Williams, Jr.	Reg.	No.	24	949
	Liane L. Churney	Reg.	No.	40	694
	Brian R. Tumm	Reg.	No.	36	328
	Robert J. Sayfie	Reg.	No.	37	714

Encl: Copy of Search Report issued June 25, 2003 in European Application No. 01108402.7

Form PTO-1449 and one copy of each cited reference

Postal Card

110.0703

SEP 0 3 2003 TC 1700

								Exp	ress M	ail Lab	el No.:	None
INFORM DISCLO CITAT		Ser.No.	Express Mail Label No.: None Toshiaki MoTONAGA et al. 09/825 578 Filed : April 3, 2001 9940 Atty.Ref.: OPS Case 529 1756									
Examiner Initial*		Docum Numbe		U.S Date	. PA	ATENT DO	CUMEN	ITS	Class	Sub Class	Fil	
Iniciai	AA		9 115	05/1997	Ka	wano et	al.				Dat	<u>e</u>
	AB	5 90	7 393	05/1999	Ka	wano et	al.					
	AC	5 91	6 712	06/1999	Mi	yashita	et al	•	·			
	AD	5 93	8 897	08/1999	Is	ao et al	•					
	AE				-							
	AF											
	AG											·
	AH					· ·-						
	AI					 -						. —
	AJ											
	AK								,			
				FORE	GN	PATENT I	DOCI IMI	ENTS				
		cumen umber	t	Date	. 021	Country		Clas	s	Sub Class		lation No
A			244212	09/19	97	Japan		With Engl	Engli ish-la	sh trans	slation Abstract	and
A	М	*										
A	N											
A	0							-				
A	P										<u>. </u>	
						<u> </u>		<u>.</u>				
	OTHE R	R DO	CUMENTS	S (Includ	ling	Author	, Tit	le, I	Date, 1	Pages,	Etc.)	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

Form PTO-1449 (Modified)

AS

EXAMINER

125.12/01

DATE CONSIDERED

Page <u>1</u> of <u>1</u>